Methods of Synthesis of Controlled Random Tests

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Abstract. Controlled random tests, methods of their generation, main criteria used for their synthesis, such as the Hamming distance and the Euclidean distance, as well as their application to the testing of both hardware and software systems are discussed. Available evidences suggest that high computational complexity is one of the main drawbacks of these methods. Therefore we propose a technique to overcome this problem. A method for synthesizing multiple controlled random tests based on the use of the initial random test and addition operation has been proposed. The resulting multiple tests can be interpreted as a single controlled random test. The complexity of its construction is significantly lower than the complexity of the construction of classical random tests. Examples of generated tests as well as estimates of their effectiveness compared to other solutions have been presented in experimental studies.

Keywords: random tests, controlled tests, multiple tests, Hemming distance, Euclidean distance

1 Introduction

Among the black box techniques, random testing is generally regarded as a very effective technique for testing modern hardware and software systems [1–7]. All modifications of random testing are united by the controllability principle for test pattern generation [1, 4, 7–12]. These tests are constructed based on the calculation of certain characteristics for the controlled selection of another random test set [1].

The use of controlled random tests is characterized by greater efficiency compared with other types of tests that has been confirmed in practice many times [1, 4, 12–17]. It should be noted that the need to sort potential candidates for test sets and calculate the numerical characteristics for them significantly increases the complexity of constructing controlled random tests [1, 4, 12, 13, 16].

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The purpose of this paper is to develop a method for constructing multiple controlled tests based on the initial controlled random test of a lesser length constructed by known methodologies [1, 4, 12, 13, 16] The initial test is used to construct subsequent tests of multiple controlled random tests in the form of simple modifications that do not require further analysis or computational costs. The resulting multiple controlled random tests can be interpreted as a single random test or used for periodic testing in applications with time limited test procedures.

2 Analysis of controlled random tests

All existing methods for constructing controlled random tests are based

on the assertion which is explained below [1, 12, 13, 15]. Each subsequent test set of the controlled random tests should be constructed such that it is as different (distant) from all previously generated test sets as possible.

For methods of controlled random testing used to test digital devices and software with m inputs and the space of input patterns consisting of 2^m binary sets (vectors), the following definitions are correct [1, 7, 13]

Definition 1. The test (T) is a set of $2 <= q <= 2^m$ test sets:

$\{T_0, T_1, T_2, ..., T_{q-1}\}$ where $T_i = t_{i,m-1}, t_{i,m-2}, ..., t_{i,2}, t_{i,1}, t_{i,0}$ and $t_{i,l} \in \{0, 1\}$

Definition 2. A controlled random test, where $CRT = \{T_0, T_1, T_2, ..., T_{q-1}\}$, is a test that includes $q < 2^m$ m-bit randomly generated test patterns denoted by T_i, where $i \in \{0, 1, 2, ..., q-1\}$, and where $T_i = t_{i,m-1}, t_{i,m-2}, ..., t_{i,2}, t_{i,1}, t_{i,0}$ and $t_{i,l} \in \{0, 1\}$, such that T_i satisfies some criterion or criteria obtained on the basis of previous test patterns $\{T_0, T_1, T_2, ..., T_{i-1}\}$.

Hamming distance and Euclidean distance are often used as difference measures between the test pattern T_i and previously generated patterns [1, 11, 18]. In this case, the measures apply to the binary test pattern T_i and T_j. The Hamming distance $\mathrm{HD}(T_i, T_j)$ is computed as the weight $\mathrm{w}(T_i \oplus T_j)$ of the vector $T_i \oplus T_j$ according to the following formula (1):

$$\mathrm{HD}(T_i, T_j) = \mathrm{w}(T_i \oplus T_j) = \sum_{l=0}^{m-1} (t_{i,l} \oplus t_{j,l}). \tag{1}$$

Euclidean distance $\mathrm{ED}(T_i, T_j)$ is computed according to the formula (2).

$$\mathrm{ED}(T_i, T_j) = \sqrt{\sum_{l=0}^{m-1} (t_{i,l} - t_{j,l})^2} = \sqrt{\sum_{l=0}^{m-1} (t_{i,l} \oplus t_{j,l})} = \sqrt{\mathrm{HD}(T_i, T_j)}. \tag{2}$$

To generate the test pattern T_i, when $i > 2$, total values of the distances between T_i and all previous patterns $(T_0, T_1, T_2, \ldots, T_{i-1})$ are used [1, 5, 10, 11, 16, 19]. Thus, for the next pattern T_i, the total value of the distances with respect to $(T_0, T_1, T_2, \ldots, T_{i-1})$ constitutes the following:

$$\mathrm{THD}(T_i) = \sum_{j=0}^{i-1} \mathrm{HD}(T_i, T_j);\ \mathrm{TED}(T_i) = \sum_{j=0}^{i-1} \mathrm{ED}(T_i, T_j). \tag{3}$$

Here, $\mathrm{THD}(T_i)$ and $\mathrm{TED}(T_i)$ stand for the total Hamming distance and total Euclidean distance, respectively. The new pattern T_i should be chosen to make the total distances $\mathrm{THD}(T_i)$ and $\mathrm{TED}(T_i)$ maximal [1].

According to the methods of constructing controlled random tests outlined above, the new test set T_i is selected so that difference metrics (3) take the maximum value [1, 12, 13, 15, 16, 20]. Note that difference metrics (3) are characterized by a significant computational complexity, which increases with the growth of the index i of the test set T_i.

As shown in [14, 20], the minimum Hamming distance $\min HD(T_i, T_j)$ or the Euclidean distance $\min ED(T_i, Tj)$ is a more efficient metrics for the generation of a controlled random test. According to the method of synthesis of tests discussed in [14], the subsequent test set T_i is selected from possible candidates for the tests by the criterion of the maximum value

$$\min_{j \in \{0,1,\ldots,i-1\}} HD(T_i, T_j) \quad \text{or} \quad \min_{j \in \{0,1,\ldots,i-1\}} ED(T_i, T_j) \tag{4}$$

which provides the maximum distance (difference) of the test set T_i from all previously generated sets $\{T_0, T_1, T_2, ..., T_{i-1}\}$. If the maximum value of (4) is achieved, it also maximizes values $THD(T_i)$ and $TED(T_i)$ according to (3) [20].

Let us define a multiple controlled test based on the methodology of single step controlled random tests.

Definition 3. The multiple controlled random test $MCRT_r$ consists of r single step controlled random tests $CRT(0), CRT(1), CRT(2), \ldots, CRT(r-1)$, each of which includes q test sets. In addition, the test $CRT(0)$ satisfies Definition 2 and subsequent tests $CRT(i)$, $i \in \{1, 2, 3, \ldots, r-1\}$ are constructed according to certain algorithms such that each subsequent test $CRT(i)$ meets a certain criterion or criteria derived from previous tests $CRT(0)$, $CRT(1)$, $CRT(2)$, ..., $CRT(i$ - 1).

Let us consider the Hamming and the Euclidean distance for two tests $CRT(k)$ and $CRT(l)$. Initially, we note that the Hamming distance $HD(CRT(k), CRT(l))$, which is the same as the number of distinct components $T_{k,i}$ and $T_{l,i}$ of the initial test $CRT(k)$ and the constructed one $CRT(l)$, can be considered as a prerequisite which the test $CRT(l)$ should meet. It is clear that a necessary requirement in terms of the maximum difference with which $CRT(k)$ and $CRT(l)$ should comply is the lack of matching sets $T_{k,i}$ and $T_{l,i}$ in them, which is equivalent to the inequality $T_{l,i} \neq T_{k,i}, i \in \{0, 1, 2, \ldots, q-1\}$.

The Euclidean distance for $CRT(k)$ and $CRT(l)$ is defined as:

$$ED(CRT(k), CRT(l)) = \sqrt{\sum_{i=0}^{q-1} (T_{i,k} - T_{i,l})^2}. \tag{5}$$

In order to use more effective criteria for estimating the quality of the controlled random test in the construction of the test $CRT(i)$, let us determine the maximum value of the Hamming distance $MHD(CRT(i))$ and the maximum value of the Euclidean distance $MED(CRT(i))$ as follows:

$$
\begin{aligned}
MHD(CRT(i)) = &\max_{CRT_v(i), v\in\{0,\dots,w\}}\{\min_{j\in\{0,1,\dots,i-1\}} HD(CRT_1(i), CRT(j)),\dots,\\
&\min_{j\in\{0,1,\dots,i-1\}} HD(CRT_w(i), CRT(j))\};\\
MED(CRT(i)) = &\max_{CRT_v(i), v\in\{0,\dots,w\}}\{\min_{j\in\{0,1,\dots,j-1\}} ED(CRT_1(i), CRT(j)),\dots,\\
&\min_{j\in\{0,1,\dots,i-1\}} ED(CRT_w(i), CRT(j))\}.
\end{aligned}
\tag{6}
$$

According to given metrics (6), the subsequent controlled random test $CRT(i)$ is selected from the set $\{CRT_1(i), CRT_2(i), \dots, CRT_w(i)\}$ of to test candidates based on the criterion of the maximum minimum Hamming and Euclidean distances with respect to previously generated controlled random tests $CRT(j) = \{CRT(0), CRT(1), \dots, CRT(i-1)\}$.

3 Method for generating multiple controlled random tests

Let us use addition as the main operation in the construction of multiple random tests. It will make it possible to provide the minimal computational complexity in the construction of multiple random tests $MCRT_r$. Indeed, all subsequent tests $CRT(1), CRT(2), \dots, CRT(r-1)$ can be easily constructed based on $CRT(0)$ by a single application of addition for each test set.

According to Definition 2, the controlled random test CRT consists of q test sets T_i, $i \in \{0, 1, 2, \dots, q-1\}$, each of which represents a m-bit binary vector $T_i = t_{i,m-1}t_{i,m-2}, \dots, t_{i,2}, t_{i,1}, t_{i,0}$, where $t_{i,l} \in \{0, 1\}$. Thus, test sets T_i of the controlled random test CRT can be interpreted as $g = 2^m$-ary data $T_i \in \{0, 1, 2, \dots, 2^m-1\}$. For example, the test $CRT = \{0011, 0110, 1100, 0101, 1000\}$ can be represented as a set of 16-ary data $CRT = \{3, 6, 12, 5, 8\}$ (in the decimal system). If the initial test is $CRT(k) = \{T_0(k), T_1(k), T_2(k), \dots, T_{q-1}(k)\}$, the ratio that is used to obtain a new test $CRT(l) = \{T_0(l), T_1(l), T_2(l), \dots, T_{q-1}(l)\}$ takes the following form:

$$T_i(l) = T_i(k) + d \bmod 2^m; i = \overline{0, q-1}. \tag{7}$$

In the given ratio, the parameter $d \in \{1, 2, 3, \dots, 2^m-1\}$ is used to achieve the difference between test sets and, accordingly, between tests $CRT(l)$ and $CRT(k)$. This parameter is crucial for achieving the maximum difference of the test $CRT(l)$ from the test $CRT(k)$ in terms of the previously defined metrics. For relation (7) the following proposition is true.

Proposition 1. If the test $CRT(l)$ is derived from the initial test $CRT(k)$ based on relation (7) for the parameter $d \in \{1, 2, 3, \ldots, 2^m - 1\}$, then using the value $2^m - d$ as the parameter for the test $CRT(l)$ and using the same relation (7) we obtain the initial test $CRT(k)$. This proposition follows from the equality $d + 2^m - d \bmod 2^m = 0$.

Example 1. When $m = 4$ for the initial test $CRT(k) = \{3, 6, 12, 5, 8\}$ and the parameter $d = 8$, according to (7), we obtain $CRT(l) = \{11, 14, 4, 13, 0\}$. Using $CRT(l) = \{11, 14, 4, 13, 0\}$ as the initial test and the same value $d = 8$, we obtain the test $CRT(k) = \{3, 6, 12, 5, 8\}$, which corresponds to the Proposition 1. For the same initial test $CRT(k) = \{3, 6, 12, 5, 8\}$ and the other parameter $d = 5$, we will have a different result, namely, $CRT(l) = \{8, 11, 1, 10, 13\}$.

Example 2. For the test $CRT(k) = \{3, 7, 0, 6, 2, 5, 1, 4\}$ constructed for $m = 3$ and parameter $d = 4$, according to (7), we find that $CRT(l) = \{7, 3, 4, 2, 6, 1, 5, 0\}$. For the same initial test and parameter $d = 5$, we will have a different result, i.e., $CRT(l) = \{0, 4, 5, 3, 7, 2, 6, 1\}$. Note that, in the given example, tests include various octal data values.

In the analysis of the above examples, in each of which two new tests obtained according to (7) are represented, the question arises as to which of these two tests is more effective for multiple testing. Thus, the problem arises of determining the optimal parameter d when using the Euclidean distance as a quality metric for multiple tests. For $ED(CRT(k), CRT(l))$, where the test $CRT(l)$ is obtained according to (7) we can use the following theorem [21].

Theorem 1. The Euclidean distance $ED(CRT(k), CRT(l))$ for tests $CRT(k)$ and $CRT(l)$, where $CRT(k) = \{T_0(k), T_1(k), T_2(k), \ldots, T_{q-1}(k)\}$ consists of $q = 2^m$ m-bit nonrecurring randomly generated test sets $T_i(k) \in \{0, 1, 2, \ldots, 2^m - 1\}$, and where test sets $T_i(l)$ are obtained according to the expression $T_i(l) = T_i(k) + d \bmod 2^m, i = \overline{0, q-1}$, is calculated as

$$ED(CRT(k), CRT(l)) = \sqrt{2^m d(2^m - d)}. \quad (8)$$

Example 3. The Euclidean distance for tests $CRT(k) = \{3, 7, 0, 6, 2, 5, 1, 4\}$ and $CRT(l) = \{7, 3, 4, 2, 6, 1, 5, 0\}$ is defined as $ED(CRT(k), CRT(l)) = [(3-7)^2 + (7-3)^2 + (0-4)^2 + (6-2)^2 + (2-6)^2 + (5-1)^2 + (1-5)^2 + (4-0)^2]^{1/2} = \sqrt{128}$ Note that the same result ($d = 4$ and $m = 3$) we obtain using 8.

Values of Euclidean distances for the case $m = 3$ and possible values of d are given in Table 1.

Table 1. Values of Euclidean distance for m=3

d	1	2	3	4	5	6	7
$ED(CRT(k), CRT(l))$	$\sqrt{56}$	$\sqrt{96}$	$\sqrt{120}$	$\sqrt{128}$	$\sqrt{120}$	$\sqrt{96}$	$\sqrt{56}$

For the above Theorem 1 we have the following corollary [21].

Corollary 1. The Euclidean distance value $ED(CRT(k), CRT(l))$ will take the maximum value when $d = 2^{m-1}$, which corresponds to the solution of the equation

$$\frac{\partial\sqrt{2^m d(2^m - d)}}{\partial d} = 0$$

The validity of this corollary is confirmed by the results shown in Table 1, where for $d = 2^{m-1} = 2^{3-1} = 4$ the Euclidean distance takes the maximum value of $\sqrt{128}$

Corollary 2. The Euclidean distance $ED(CRT(k), CRT(l))$ obtained for the parameter d is equal to the Euclidean distance of the parameter $2^m - d$, which follows from the equality

$$\sqrt{2^m d(2^m - d)} = \sqrt{2^m(2^m - d)(2^m - (2^m - d))}.$$

This property is illustrated by numerical values of the Euclidean distance shown in Table 1.

Corollary 3. The value of the Euclidean distance $ED(CRT(k), CRT(l)) = \sqrt{2^m d(2^m - d)}$ obtained according to (8) for tests $CRT(k)$ and $CRT(l)$ consisting of $q = 2^m$ m-bit data $\{0, 1, 2, \ldots, 2^m - 1\}$ can be used as the mean Euclidean distance $AED(CRT(k), CRT(l))$ equal to $\sqrt{qd(2^m - d)}$, between tests $CRT(k)$ and $CRT(l)$ that include $q < 2^m$ test sets.

For Example 1 and test $CRT(l) = \{11, 14, 4, 13, 0\}$ obtained based on the initial test $CRT(k) = \{3, 6, 12, 5, 8\}$ at $d = 8$, according to (7), we find that

$$AED(CRT(k), CRT(l)) = \sqrt{5 \times 8 \times (2^4 - 8)} = \sqrt{320}$$

Note that, for these tests, the Euclidean distance is strictly equal to its average value. Indeed, $ED(CRT(k), CRT(l)) = [(3-11)^2 + (6-14)^2 + (12-4)^2 + (5-13)^2 + (8-0)^2]^{1/2} = \sqrt{320}$.

Corollary 4. If the Euclidean distance $ED(CRT(k), CRT(l))$ between controlled random tests $CRT(k)$ and $CRT(l)$ according to Theorem 1 is equal to $\sqrt{2^m d_l(2^m - d_l)}$ and, for tests $CRT(k)$ and $CRT(n)$, $ED(CRT(k), CRT(n)) = \sqrt{2^m d_n(2^m - d_n)}$, then $ED(CRT(l), CRT(n)) = \sqrt{2^m d_c(2^m - d_c)}$, where $d_c = d_l - d_n \bmod 2^m$.

In accordance with Example 2 $CRT(l) = \{0, 4, 5, 3, 7, 2, 6, 1\}$ and $CRT(n) = \{7, 3, 4, 2, 6, 1, 5, 0\}$, from the Corollary 4, we obtain that $d_c = d_l - d_n \; mod \; 2^m = 5 - 4 \; mod \; 2^3 = 1$ and

$$ED(CRT(l), CRT(n)) = \sqrt{2^m d_c(2^m - d_c)} = \sqrt{2^3 \times 1 \times (2^3 - 1)} = \sqrt{56}.$$

4 Method for generating multiple controlled random tests

As a basis for constructing multiple controlled random tests

$$MCRT_r = \{CRT(0), CRT(1), CRT(2), \ldots, CRT(r-1)\}, \quad (9)$$

we use relation (7), which is characterized by the minimal computational complexity in obtaining subsequent tests $CRT(1), CRT(2), \ldots, CRT(r-1)$ based on the initial one $CRT(0)$.

Then, the maximum minimum Hamming distance $MHD(CRT(k), CRT(l))$ and the maximum minimum Euclidean distance $MED(CRT(k), CRT(l)), k \neq l \in \{0, 1, 2, \ldots, r-1\}$, according to (7), will be used in the construction of multiple random tests (9) as measures of efficiency.

Let us successively consider multiple controlled random tests $MCRT_r$ of various multiplicity ranging from double tests $MCRT_2$ that consist of $CRT(0)$ and $CRT(1)$, where the second test $CRT(1)$ is generated based on the initial test $CRT(0)$ according to (7). According to Corollary 1, the optimum value of the parameter d in order to obtain $CRT(1)$ is 2^{m-1}. In this case, the Euclidean distance between the tests $CRT(0)$ and $CRT(1)$ takes the maximum value that maximizes the difference between these tests and the maximum effectiveness of their joint application.

Let us consider the following theorem for tests $MCRT_r$ with the multiplicity $r > 2$ [21].

Theorem 2. The maximum value $MHD(CRT(k), CRT(l))$ with which the tests $CRT(k)$ and $CRT(l)$ $(k \neq l \in \{0, 1, 2, \ldots, r-1\})$ of the multiple controlled random test $MCRT_r$ that consists of $r > 2$ controlled random tests $\{CRT(0), CRT(1), CRT(2), \ldots, CRT(r-1)\}$, each of which contains $q \leq 2^m$ m-bit test sets, should comply is achieved in the case of the maximum minimum value $d_k - d_l$ $(k \neq l \in \{0, 1, 2, \ldots, r-1\})$, and $d_k \neq d_l \in \{1, 2, \ldots, 2^m - 1\}$.

Based on the theorem, we can conclude that for the general case of the multiple test $MCRT_r$ optimal values of parameters $d_1, d_2, \ldots, d_{r-1}$ are the values that divide the range of integers of $0 - 2^m$ into regular intervals and are calculated according to the following relation:

$$d_i = \left\lfloor \frac{i2^m}{r} + 0.5 \right\rfloor \; i \in \{1, 2, \ldots, r-1\}. \quad (10)$$

In the case of the triple random test $MCRT_3$, in order to obtain the second $CRT(1)$ and third $CRT(2)$ tests based on the initial test $CRT(0)$, it is necessary to use optimum combinations of parameters d_1 and d_2 according to (10) used to obtain tests $CRT(1)$ and $CRT(2)$ according to (7). Correspondingly, for triple random tests,

$$d_1 = \lfloor 1 \times 2^m/3 + 0.5 \rfloor, \; and \; d_2 = \lfloor 2 \times 2^m/3 + 0.5 \rfloor.$$

For $m = 3$, we find that $d_1 = 3$ and $d_2 = 5$ and, for $m = 4$, $d_1 = 5$ and $d_2 = 11$.

Let us consider $MCRT_3 = \{CRT(0), CRT(1), CRT(2)\}$ when $m = 4$ using $d_1 = 5$ and $d_2 = 11$. The Euclidean distance between the tests $CRT(0)$ and $CRT(1)$ is calculated as follows $ED(CRT(0), CRT(1)) = \sqrt{16 \times 5 \times (16 - 5)} = \sqrt{880} = 29.7$. Other values of Euclidean distances for an arbitrary value d are shown in Table 2. According to this table, the value of the Euclidean distance is

Table 2. Values of the Euclidean distance for $m = 4$

d	1	2	3	4	5	6	7	8
$ED(CRT(k), CRT(l))$	15.5	21.2	24.9	27.7	29.7	30.9	31.7	32.0
d	9	10	11	12	13	14	15	16
$ED(CRT(k), CRT(l))$	31.7	30.9	29.7	27.7	24.9	21.2	15.5	0

$ED(CRT(0), CRT(2)) = 29.7$. At the same time, in accordance with Corollary of 4, the distance between tests $CRT(1)$ and $CRT(2)$ is determined for d equal to $d_2 - d_1 = 11 - 5 = 6$ as $ED(CRT(1), CRT(2)) = 29.7$.

The analysis of given values of Euclidean distances for the considered $MCRT_3$ indicates that $MED(CRT(k), CRT(l)) = 29.7$ for $k \neq l \in \{0, 1, 2\}$ according to (6) and $TED(CRT(2)) = ED(CRT(2), CRT(0)) + ED(CRT(2), CRT(1)) = 29.7 + 29.7 = 59.4$ according to (3) take the maximum value.

For the quadruple test $MCRT_4 = CRT(0), CRT(1), CRT(2), CRT(3)$ using (10), e.g., for $m = 4$, we find that $d_1 = 4, d_2 = 8$ and $d_3 = 12$. The values of the distances between any two tests $MCRT_4$ are given in Table 3. As can be seen

Table 3. Values of the Euclidean distance for the test $MCRT_4$

	$CRT(0)$	$CRT(1)$	$CRT(2)$	$CRT(3)$
$CRT(0)$	–	27.7	32.0	27.7
$CRT(1)$	27.1	–	27.7	32.0
$CRT(2)$	32.0	27.7	–	27.7
$CRT(3)$	27.7	32.0	27.7	–

from Table 3, the value $MED(CRT(k), CRT(l)), k \neq l \in \{0, 1, 2, 3\}$ for $MCRT_4$ takes the maximum possible value of 27.7.

5 Experiments

As a measure of the effectiveness of multiple controlled random test $MCRT_r$ we used the metric $E(k, 2^m)$ introduced in [7] in order to construct subsequent test sets in the generation of the single-step controlled random test. In the case of multiple tests similar characteristic for the subsequent test $CRT(i)$ is formulated and can be determined as follows.

Definition 4. The additional number of binary combinations over all possible k out of 2^m bits generated by test sets of the test $CRT(i)$ with respect to the binary combinations generated by previous tests of the multiple test $CRT(0), CRT(1), CRT(2), \ldots, CRT(i-1)$ is the measure of effectiveness $E(k, 2^m)$ for the subsequent controlled test $CRT(i)$.

Obviously, the larger the value of this metric, the more effective is the subsequent controlled test $CRT(i)$, which together with the previous tests makes it possible to achieve maximum efficiency. Note that in previous sections it was shown that in order to achieve the maximum efficiency of multiple controlled random tests $MCRT_r$ the Euclidean distance for the test $CRT(i)$ should be maximum in relation to previously generated tests $CRT(0), CRT(1), \ldots, CRT(i-1)$.

The problem of testing storage devices was used for the comparative analysis of the effectiveness of multiple controlled random tests $MCRT_r$ [20]. First, let us consider a storage device that consists of $2^3 = 8$ memory cells. In order to test it, we used the test $CRT(0)$, which includes all possible three-bit addresses generated according to the scheme of march tests [13, 18]. In the formation of the next address the initial zero state of the memory cell is changed to a one state. Thus, the initial zero state of all cells of the storage device is changed to the one state. Note that values $ED(CRT(0), CRT(1))$ for two tests $CRT(0), CRT(1)$ and $m = 3$ are given in Table 1. The test obtained according to (7) for all possible values of the parameter d was used as the second controlled random test $CRT(1)$. The resulting values of the metric $E(k, 2^m)$ for the double test $MCRT_2$ that consists of tests $CRT(0)$ and $CRT(1)$ are shown in Table 4. As can

Table 4. Estimation of the effectiveness of the double test for the storage device consisting of eight memory cells ($2^m = 8$) for $k = 3, 4, 5, 6$

d	$E(k, 2^m)$ - additional number of combinations on all possible k from 2^m bits			
	$E(3,8)$	$E(4,8)$	$E(5,8)$	$E(6,8)$
1	42	105	140	105
2	72	165	200	135
3	90	195	220	140
4	96	204	224	140
5	90	195	220	140
6	72	165	200	135
7	42	105	140	105

be seen from given numerical values, the effectiveness of the double test is in strict accordance with the values $ED(CRT(0), CRT(1))$ listed in Table 1. Indeed, for $d = 1$ and $d = 7$ the Euclidean distance between $CRT(0)$ and $CRT(1)$ equals the minimum value $\sqrt{56}$ (Table 1), respectively, and the number of additional binary combinations is minimum for all the values k. At the same time, for $d = 4$ and, consequently, for the maximum value $ED(CRT(0), CRT(1)) = \sqrt{128}$ the number of additional combinations is maximum (Table 4). The results in

Table 4 confirm the validity of theoretical provisions and, above all, the validity of Theorem 1.

When using controlled random tests, in most cases, the number q of test sets is less than the total number of 2^m m-bit input patterns [1, 12–15]. Accordingly, the validity of the results of Theorem 1 for the case $q < 2^m$ and, above all, for Corollary 3 is significant for the proposed method of constructing controlled random tests. According to this corollary, the Euclidean distance $ED(CRT(k), CRT(l)) = \sqrt{2^m d(2^m - d)}$ obtained for $q = 2^m$ can be used as a mean value for $q < 2^m$ and can be determined by the relation $AED(CRT(k), CRT(l)) = \sqrt{qd(2^m - d)}$. It is obvious that, according to Corollary 3, the error between the experimental values AED(CRT(k),CRT(l)), and theoretical values should decrease with increasing value of q. When $q = 2^m$, experimental and theoretical values should be equal, which is confirmed by practical results given in Fig 1. The figure shows averaged values of deviations of the

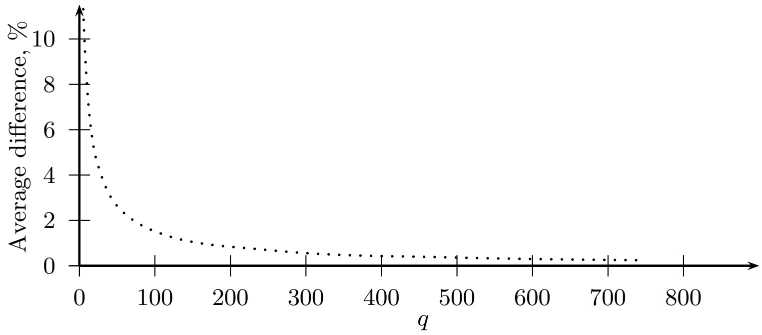

Fig. 1. Average difference value (%) of the experimental value $AED(CRT(k), CRT(l))$ from the theoretical value obtained by the formula for $m = 10$.

experimental data from the theoretical results depending on q. As can be seen from Fig. 1, even for $q > 100$, the experimental results hardly differ from the theoretical values, which confirms the validity of using the results of Theorem 1 to generate controlled random tests.

Finally, to confirm the proposed solution we have compared the coverage of Multiple Random Tests and Multiple Controlled Random Tests in terms of number of generated binary combinations for all arbitrary k out of N bits. Using both methods, we had generated multiple tests consisting of $r = 4$ tests with $q = 3$ subtests. In the first case all tests and subtests were generated randomly. In case of Multiple Controlled Random Tests only first test $CRT(0)$ was generated randomly whereas $CRT(1), CRT(2)$ and $CRT(3)$ were generated with respect to Theorem 2 and equation. (7). The obtained average results for 5000 experiments are shown in the Figure 2a and 2b. The x-axis represents the test number $CRT(i)$, and the y-axis – the number (in percent) of binary combinations for all arbitrary $k = 3$ and k=4 out of $N = 64$ bits. For Fig. 2, we observe

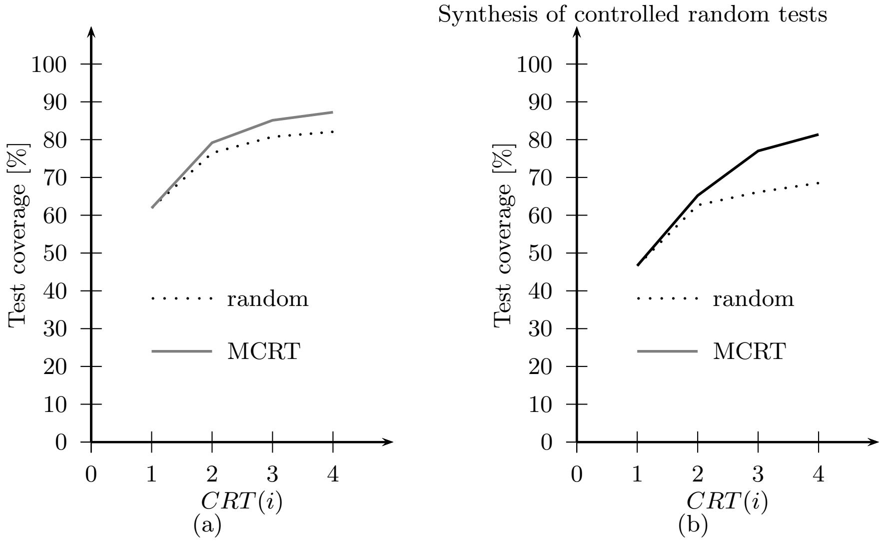

Fig. 2. The coverage of all arbitrary k out of N bits for Multiple Random Tests and Multiple Controlled Random Test:
a) k=3 and N=64, b) k=4 and N=64

that in both cases curves rise sharply and exhibits a smooth behavior. We observe that $MCRT_r$ gives us a bit higher level of fault coverage as in case of random patterns. The same time we should noted that $MCRT_r$ is characterized by easier computational method of test patterns generation in compare to other techniques.

6 Conclusion

The concept of multiple controlled random tests has been considered. Existing solutions have been analyzed, and a formal method for generating multiple tests has been proposed. The efficiency of using the Euclidean distance to construct multiple tests has been confirmed based on the experimental results for the case of multiple tests of storage devices. Finally the efficiency of proposed Multiple Controlled Random Tests has been tested. The experimental study demonstrate a high efficiency of the proposed solution.

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